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Information Disclosure Citation					10/706,637 Docket Number		Group Art I		et al. Filing Date			
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14_	178 1	8 2005		021208.0247 2822 November 12, 200								
3		<u> </u>		U.\$	S. PATENT DOCUMENTS							
K	U.: 7 A. 5616177 4/1/1997			NAME	CLASS		SUBCLASS		FILING DATE			
26	Α.	5616177 4/1/1997			Yamada		117	102		2/22/95		
Ц	В	5879459 3/09/1999			Gadgil et al.		118	715		8/29/97		
Ш	c.	5916365	6/29/1999		Sherman		117		92	8/	16/96	
\coprod	D.	5930046	7/27/1999		Solberg et al.		359		80	9/	30/97	
Ш	E.	5944964	8/31/1999	<u> </u>	Solberg et al.		204	19	2.26	2/	13/97	
Ш	F	6015590	1/18/2000		Suntola et al.		427	25	5.23	09/25/96		
Щ_	G.	6144060	11/7/2000		Park et al.		257	3	310	7/31/98		
Ш	Н.	6174377	1/16/2001		Doering et al.		118	7	729	1/4/99		
	l.	6200893	3/13/2001		Sneh		438		85	3/11/99		
	J.	6200866 3/13/2001			Ma et al.		438		299		9/30/99	
Щ_	К.	2001/0024387	Raaijmakers et al.		365	200		2/22/01				
	<u>L.</u>	6319439 11/20/2001			Lee et al.		264		81	2/25/00		
Щ	М.	6335240	1/1/2002	Kim et al.	<u> </u>	438		253		1/6/99		
\perp	N.	6342277	1/29/2002		Sherman		427	562		41	14/99	
10	4 O. 2002/0013487 1/31/2002				Norman et al.		556	į	7 2/22/01		22/01	
		·		FORE	IGN PATENT DOCUMENT	S						
		DOCUMENT NO.	DATE		COUNTRY		CLASS	SUB	CLASS	TRAN	SLATION NO	
37	P.	62221102	09/29/1987	JP	(with English abstract)		H01F	. 4	1/14		х	
Ц	Q.	00/38191	06/29/2000		wo		G11C 1		1/15	x		
	R.	02/09126	01/31/2002		wo		H01F	10	0/32	х		
Ш	s.	02/09158	01/31/2002		wo		H01L	2.	1/00	х		
11	1 T	01/88972	11/22/2001		wo		H01L	21	/321	х		
		NON-PATENT	DOCUMENTS -	DOCUN	IENT (Including Author, Ti	itle, Sc	urce, and Pe	rtinent P	ages)			
70	U.	Addison, C.C. et al. "Th State", J. Chem. Soc., p		re of Anh	ydrous Copper Nitrate, and	its Mo	ecular Weight	in the Va	pour		1958	
Ц	V.	Akerman, J.J et al., "Ide wide web, physics.ucsd			omagnetic-Insulator-Ferroma , pp. 1-6,	agnetic	Thin Film Str	uctures",	World-		rinted 14/2002	
	w.	Bobo, J.F. et al., *Spin-c Physics, vol. 83, No. 11		ling June	tions with Hard Magnetic la	yer Pin	ning", <i>Journa</i>	of Applie	ed .	11	1998	
Щ	X.	Daughton, J.M., World-	wide web nve.com	n/otherbi	z/mram2.pdf, *Advanced Mf	RAM C	oncepts*, pp.	1-6		02/0	7/2001	
31	1 Y.	Fereday, R.J. et al., "An	hydrous Cobalt (III) Nitrat	e", Chemical Communication	ns, pp.	271			1	1968	
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		PLANDAT					(hz)05					
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		DOCUMENT NO.	DATE		NAME		CLASS	SUB	CLASS	FILIN	IG DATE	
2f	A.	6358632	3/19/2002		Dickey et al.		428		690		11/10/98	
	В.	2002/0041931	4/11/2002		Suntola et al.		427	255.28		5/14/01		
Ц	C.	6391785	5/21/2002		Satta et al.		438	7	704	8/	23/00	
	D.	6416577	7/9/2002		Suntola et al.		117		88	06	/07/00	
\perp	E.	6420230	7/16/2002		Derderlan et al.		438	-	255	8/	31/00	
\perp	F.	2002/0106846	8/8/2002		Seutter et al.		438		200	2/2/01		
	G.	2002/0106846	8/8/2002		Seutter et al.		438	2	200	2	2/2/01	
	Н.	2002/0108570	8/15/2002		Lindfors		118	7	15	4/16/01		
1	l.	6441417	8/27/2002		Zhang et al.		257 295			3/28/01		
1	J.	6444495	9/3/2002	Leung et al.			438 1		118 1		11/01	
1	К.	6447607	9/10/2002	Soininen et al.			117		200		12/27/00	
\perp	L.	6448192	9/10/2002	Kaushik			438	,	785	4/16/01		
1	M.	6451119*	9/17/2002	Sneh et al.			118	7	115	11/29/00		
	N.	6451695	9/17/2002		Sneh		438	6	85	12/22/00		
1	0.	2002/0137260	9/26/2002	Leung et al. 438				118		1/11/01		
20	P.	2002/0140103	10/3/2002		Kloster et al.		257	;	67	3/	/28/01	
		· · · · · · · · · · · · · · · · · · ·		FORE	IGN PATENT DOCUMENT	s						
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		NON-PATENT	DOCUMENTS -	DOCUM	IENT (including Author, T	itie, Sc	urce, and Pe	rtinent P	ages)			
35	S.	and Development, vol. 4	43, (1/2):1999, pp.	. 89-102							1999	
	т.	Imai, Takuji, World-wide Around the Corner, pp.		abiztech	.com/nea/200008/tech_108	675.ht	ml, *100 Gbit/	inch HDD	Just	08	3/2000	
	U.	Nilsen, O et al, 'Thin File Chemistry, vol. 9, pp. 17		nthanur	n Manganite Perovskite by	the ALI	E Process", J	ournal of l	Materials		1999	
	V.	Pakrad, C.D., *Pure Tec puretechinc.com/tech_p			ead Materials," World-wide v pp. 1-2	veb,					1999	
	W.	Riihela et al., "Low Tem Ammonia" Chemical Va			N Films by an Alternate Syp 277-283.	py of T	rimethyl Alum	inum and			1996	
W	x.	Suntola, Tuomo; Handb Dynamics, Chapter 14,			l. 3, Thin Films and Epitaxy, sevier Science B.V.	Part B	: Growth Med	hanisms	and		1994	
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	11	FICARDH		· · · · · · · · · · · · · · · · · · ·		6	hros				•	
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Information Disclosure Citation in an Application					Docket Number		Group Art	Jnit Filing Da		te .		
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	U.S. PATENT DOCUMENTS											
		DOCUMENT NO. DATE			NAME		CLASS	SUBCLASS		FILIN	G DATE	
2	A.	6464779	10/15/2002	<u>.</u>	Powell et al.		117		89		19/01	
	В.	6475910	11/5/2002		Sneh	ļ	438	685		9/22/00		
1	C.	6475276	11/5/2002		Elers et al.		117		34	10.	/13/00	
	D.	6482262	11/19/2002		Elers et al.	ļ	117		34	10.	/13/00	
\perp	E.	6482740	11/19/2002		Soininen et al.		438	6	86	5/	15/01	
	F.	2002/0187084	12/12/2002		Lindfors et al.		422	1	77	7/	24/02	
Ц_	G.	6503330	1/7/2003	·	Sneh et al.	·	118	7	15	12	/22/99	
	Н.	6506352	1/14/2003		Lindfors et al.	<u> </u>	423	2	40	7/20/00		
1	I.	6524952	2/25/2003		Srinivas et al.	<u> </u>	438	6	49	6/20/00		
<u>L</u>	J.	6540838 4/1/2003 Sneh et al.					118	7	715 6/28		28/02	
_	K.	6548424 4/15/2003 Putkonen					438 785		85	4/16/01		
	L.	6551406 4 <i>/22/2</i> 003 Kilpi 118					118	7	28	12	/27/00	
	М.	6562140 5/13/2003 Bondestam et al.					118	7	15	5/	10/00	
1	N.	2003/0096468	5/22/2003		Soininen et al.	<u> </u>	438	2	00	11.	/19/02	
	Ο.	6572705	6/3/2003		Suntola et al. 118				02	1/	14/00	
20	P.	2003/0101927 6/5/2003 Raaijmakers 117 200						12	/10/02			
		4		FORE	IGN PATENT DOCUMEN	rs						
		DOCUMENT NO.	DATE		COUNTRY		CLASS	SUBC	LASS	TRAN YES	SLATION NO	
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		NON-PATENT	DOCUMENTS	- DOCUM	ENT (Including Author, 1	itle, Sc	urce, and Pe	rtinent Pa	iges)			
W.	R.				O2/SiN/CU via Structures VAc. Sci. Technology B, vo				Oxygen	Nov /	Dec. 1998	
	S.		s of Metallic Film	Growth is	n an Atomic Layer Epitaxy				Cu, Pt)		2000	
	T.	Wang, Shan X., "Advan	ced Materials for	Extremel	y High Density Magnetic R		g Heads," De	partment	of	no	date ailable	
	U. .	World-wide web, megah	naus.com/tech/we	estemdigi	tal/shitepapers/gmr_wp.sh ce Areal Density," pp. 1-4.		MR Head Tec	hnology:			/2000	
	٧.				echGMR-c.html, *Giant Ma	netore	sistive (GMR)	Heads' r	n 1-4	Pı	inted 8/2004	
1	W.	World-wide web, semico	onductor.net/sem	niconducto	or/issues/Issues/1998/feb9				•			
1,	х.	Heads Yield Data Stora	<u>-</u>								/1998 inted	
N'			.leeds.ac.uk/rese	earch/gmr.	.htm, *Giant Magnetoresist	T				02/0	4/2002	
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200	A.	6579374	6/17/2003	Bondestam et al.		118	725		1/.	25/01		
Ш	В.	2003/0121469	7/3/2003	Lindfors et al.		117	1	105		/11/02		
	C.	6599572	7/29/2003	Saanila et al.		427	24	9.18	1/	18/01		
Ш	D.	2003/0140854	7/31/2003	Kilpi		118	7	15	21	13/03 .		
.	E.	6602784	8/5/2003	Sneh		438	6	380	8/	/6/02		
	F.	2003/0150385	8/14/2003	Bondestam et al.		118	7	<u> 22</u>	3/	/6/03		
	G.	6616986	9/9/2003	Sherman		427	5	62	10/9/01			
Ш	н.	6620723	9/16/2003	Byun et al.		438		527	6/27/00			
	l.	6627268	9/30/2003	Fair et al.		427	427 533		5/3/01			
	J.	2003/0183171	10/2/2003	Sneh et al.		118		724		27/03		
	К.	6630401	10/7/2003	Sneh		438		680		/6/02		
	L.	6630030	10/7/2003	Suntola et al.		118		7 [.] 28		/4/00		
	М.	6632279	10/14/2003	Ritala et al.		117	1	101	10.	/13/00		
	N.	6635965	10/21/2003	Lee et al.		257	7	758	10	10/9/01		
	О.	6638862	10/28/2003	Sneh		438	<u> </u>	S85	8.	/6/02		
	P.	6638859	10/28/2003	Sneh et al.		438	<u> </u>	80	9/	27/02		
	Q.	6638810	10/28/2003	Bakli et al.		438	2	240	11	1/5/01		
	R.	6652924	11/25/2003	Sherman		427 576		576	5/	24/01		
	s.	6660126	12/9/2003	Nguyen et al.		156 345.34		5.34	3.	/2/01		
	т.	6664192	12/16/2003	Satta et al.		438	438 704		4/15/02			
Ш	U.	2004/0005753	1/8/2004	Kostamo et al.		438	222		3/20/03			
	V.	2004/0007171	1/15/2004	Ritala et al.		117		89	7/10/03			
30	W.	6679951	1/20/2004	Soininen et al.		148		240	11/	/13/01		
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W	A.	6689210	2/10/2004	Soininen et al.		117	89		7/24/02		
	В.	6720260	4/13/2004	Fair et al.		438	6	80			
	C.	2004/0076837	4/22/2004	Hein et al.		428	44	146 10/22		22/02	
	D.	2004/0076751	4/22/2004	Sherman		427	255.34		10/10/03		
\perp	E.	6727169	4/27/2004	Raaijmakers et al.		438	6:	22	8/2	23/00	
\perp	F.	2004/0083949	5/6/2004	Sherman		117	8	4	10/	22/03	
	G.	6734020	5/11/2004	Lu et al.		436	5	55 3/7/		7/01	
\perp	н.	2004/0121616	6/24/2004	Satta et al.		438	7	778		/8/03	
1	l.	6759081	7/6/2004	Huganen et al.		427		58		30/02	
\perp	J.	2004/0130029	7/8/2004	Raaijmakers et al.		257		758		15/03	
<u>L</u>	к.	6764546	7/20/2004	Raaijmakers		117		93		12/10/02	
<u> </u>	L.	6767582	7/27/2004	Elers		427	2:	253		12/00	
	M.	6777353	8/17/2004	Putkonen		438	7	785		8/03	
1	N.	2004/0161636	8/19/2004	Hujanen et al.		428	6	692		17/04	
\perp	0.	6794287	9/21/2004	Saanila et al.		438	6	74	3/2	20/03	
	Р.	6800173	10/5/2004	Chiang et al.		156		5.33	7/9/01		
\perp	Q.	6800552	10/5/2004	Elers et al.		438		680 9/1		17/02	
\downarrow	R.	2004/0202786	10/14/2004	Wongsenakhum et a	1.	427		250		3/31/04	
\perp	S.	6811814	11/2/2004	Chen et al.		427 2		248.1 1/		1/16/02	
1	Т.	6818067	11/16/2004	Doering et al.		118 71		715 4/15/02		15/02	
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	C.	5916369	06/29/99	Anders	on et al.	118	715	06/	07/95		
	D.	6387185 B2	05/14/02	Doerii	ng et al.	118	729	01/	16/01		
	E.	2003/0003635 A1 01/02/03			pe et al.	438	149	05/23/01			
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m	Q.	Omstead, Thomas, e	al.; "Filling Hi	gh-AR Structu	res Using Puls	sed Nucleation Lay	er Deposition",	09/	/2002		
20	R.	Solid State Technolo Ritala, Mikko, et al.; Nanotechnology, Vo	"Atomic Layer	Epitaxy – a V	aluable Tool f	or Nanotechnology	/?",	1	999		
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